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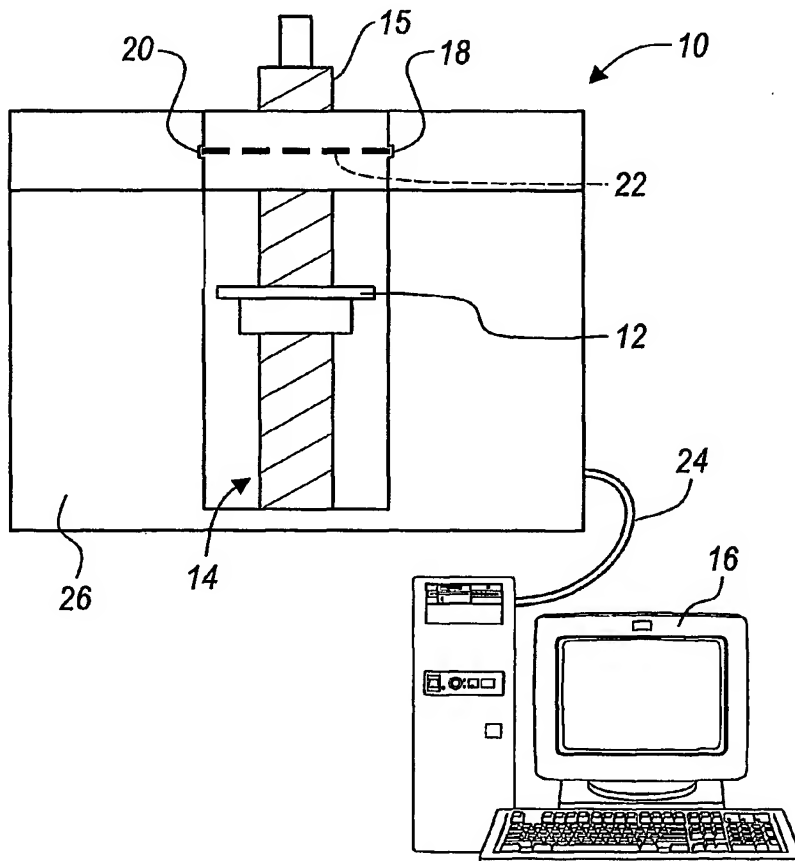
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(54) Title: LASER SYSTEM FOR MEASUREMENTS OF THE PROFILE OF OBJECTS



(57) Abstract: A system for measuring a profile of an object comprising a source creating a beam of electromagnetic energy. An electromagnetic beam receiver spaced from the source for processing an output signal proportional to the girth of the object being measured. A platform for providing rotational and vertical movement of the object being measured causing the object to obstruct a portion of the electromagnetic beam generated by the source. A processor for processing the output signal from the electromagnetic beam receiver to form a composite profile of the object measured.

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